

Notice of References Cited

Application/Control No.

10/069,103

Applicant(s)/Patent Under
Reexamination
SOUVIE ET AL.

Examiner

Yelena G. Gakh, Ph.D.

Art Unit

1743

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,234,689	08-1993	Lindauer et al.	424/401
*	B	US-4,110,626	08-1978	Katada et al.	512/2
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 04159399 A	06-1992	Japan	KOMATA et al.	
	O	WO 9926600 A1	06-1999	World Intellect	SURBLED et al.	
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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